

**Measurement of charge carrier lifetime temperature dependence in 4H-SiC power diodes**

**Velme, Enn; Udal, Andres** Abstracts of International Conference on Silicon Carbide and Related Materials : ICSCRM'99 : October 10-15, 1999, Research Triangle Park, North-Carolina, USA 1999 / paper no 394, 2 p  
[https://www.researchgate.net/publication/240833834\\_Measurement\\_of\\_Charge\\_Carrier\\_Lifetime\\_Temperature-Dependence\\_in\\_4H-SiC\\_Power\\_Diodes](https://www.researchgate.net/publication/240833834_Measurement_of_Charge_Carrier_Lifetime_Temperature-Dependence_in_4H-SiC_Power_Diodes)

**A theoretical study of electron drift mobility anisotropy in n-type 4H- and 6H-SiC**

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[https://www.researchgate.net/publication/250338907\\_A\\_Theoretical\\_Study\\_of\\_Electron\\_Drift\\_Mobility\\_Anisotropy\\_in\\_n-Type\\_4H-and\\_6H-SiC](https://www.researchgate.net/publication/250338907_A_Theoretical_Study_of_Electron_Drift_Mobility_Anisotropy_in_n-Type_4H-and_6H-SiC)